

測試報告 Test Report

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智晶光電股份有限公司
WISECHIP SEMICONDUCTOR INC.
苗栗縣竹南鎮科北二路8號
8, KEBEI RD. 2, SCIENCE PARK, CHU-NAN, TAIWAN 350, R.O.C.



以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as) :

送樣廠商(Sample Submitted By) : 智晶光電股份有限公司 (WISECHIP SEMICONDUCTOR INC.)
樣品名稱(Sample Description) : OLE DISPLAY MODULE
樣品型號(Style/Item No.) : PANEL+COG
收件日期(Sample Receiving Date) : 2014/07/09
測試期間(Testing Period) : 2014/07/09 TO 2014/07/16

=====
測試需求(Test Requested) : (1) 依據客戶指定, 進行鎘, 鉛, 汞, 六價鉻, 多溴聯苯, 多溴聯苯醚測試. (As specified by client, to test Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs contents in the submitted sample.)

(2) 依據客戶指定, 進行全氟辛酸、全氟辛烷磺酸、鹵素-氯、溴測試. (As specified by client, to test PFOA, PFOS, Halogen-Chlorine, Bromine contents in the submitted sample.)

測試方法(Test Method) : 請見下一頁 (Please refer to next pages).

測試結果(Test Results) : 請見下一頁 (Please refer to next pages).


Edison Chang / Sr. Supervisor
Signed for and on Behalf of
SGS TAIWAN LTD.
Chemical Laboratory – Taipei

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測試結果(Test Results)

測試部位(PART NAME) No.1 : 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
鎘 / Cadmium (Cd)	mg/kg	參考IEC 62321-5: 2013方法, 以感應 耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
鉛 / Lead (Pb)	mg/kg	參考IEC 62321-5: 2013方法, 以感應 耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	5
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4: 2013方法, 以感應 耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-4: 2013 and performed by ICP-AES.	2	n.d.
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	參考IEC 62321: 2008方法, 以UV-VIS 檢測. / With reference to IEC 62321: 2008 and performed by UV- VIS.	2	n.d.
鹵素(氯) / Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg	參考BS EN 14582:2007, 以離子層析 儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(溴) / Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg	參考BS EN 14582:2007, 以離子層析 儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
全氟辛烷磺酸 / Perfluorooctane sulfonates (PFOS-Acid, Metal Salt, Amide)	mg/kg	參考US EPA 3550C: 2007方法, 以液相層析/質譜儀檢測. / With reference to US EPA 3550C: 2007.	10	n.d.
全氟辛酸 / PFOA (CAS No.: 335-67-1)	mg/kg	Analysis was performed by LC/MS.	10	n.d.
多溴聯苯總和 / Sum of PBBs	mg/kg	參考IEC 62321: 2008方法, 以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 and performed by GC/MS.	-	n.d.
一溴聯苯 / Monobromobiphenyl			5	n.d.
二溴聯苯 / Dibromobiphenyl			5	n.d.
三溴聯苯 / Tribromobiphenyl			5	n.d.
四溴聯苯 / Tetrabromobiphenyl			5	n.d.
五溴聯苯 / Pentabromobiphenyl			5	n.d.
六溴聯苯 / Hexabromobiphenyl			5	n.d.
七溴聯苯 / Heptabromobiphenyl			5	n.d.
八溴聯苯 / Octabromobiphenyl			5	n.d.
九溴聯苯 / Nonabromobiphenyl			5	n.d.
十溴聯苯 / Decabromobiphenyl			5	n.d.
多溴聯苯醚總和 / Sum of PBDEs			-	n.d.
一溴聯苯醚 / Monobromodiphenyl ether			5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether			5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether			5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether			5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether			5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether			5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether			5	n.d.
八溴聯苯醚 / Octabromodiphenyl ether			5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether	5	n.d.		
十溴聯苯醚 / Decabromodiphenyl ether	5	n.d.		

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備註(Note) :

1. mg/kg = ppm ; 0.1wt% = 1000ppm
2. n.d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)
4. "-" = Not Regulated (無規格值)
5. 樣品的測試是基於申請人要求混合測試，報告中的混合測試結果不代表其中個別單一材質的含量。
(The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

PFOS參考資訊(Reference Information) : 持久性有機污染物 POPs - (EU) 757/2010

PFOS濃度在物質或製備中不得超過0.001%(10ppm)，在半成品、成品或零部件中不得超過0.1%(1000ppm)，在紡織品或塗層材料中不得超過 $1\mu\text{g}/\text{m}^2$ 。(Outlawing PFOS as substances or preparations in concentrations above 0.001% (10ppm), in semi-finished products or articles or parts at a level above 0.1%(1000ppm), in textiles or other coated materials above $1\mu\text{g}/\text{m}^2$.)

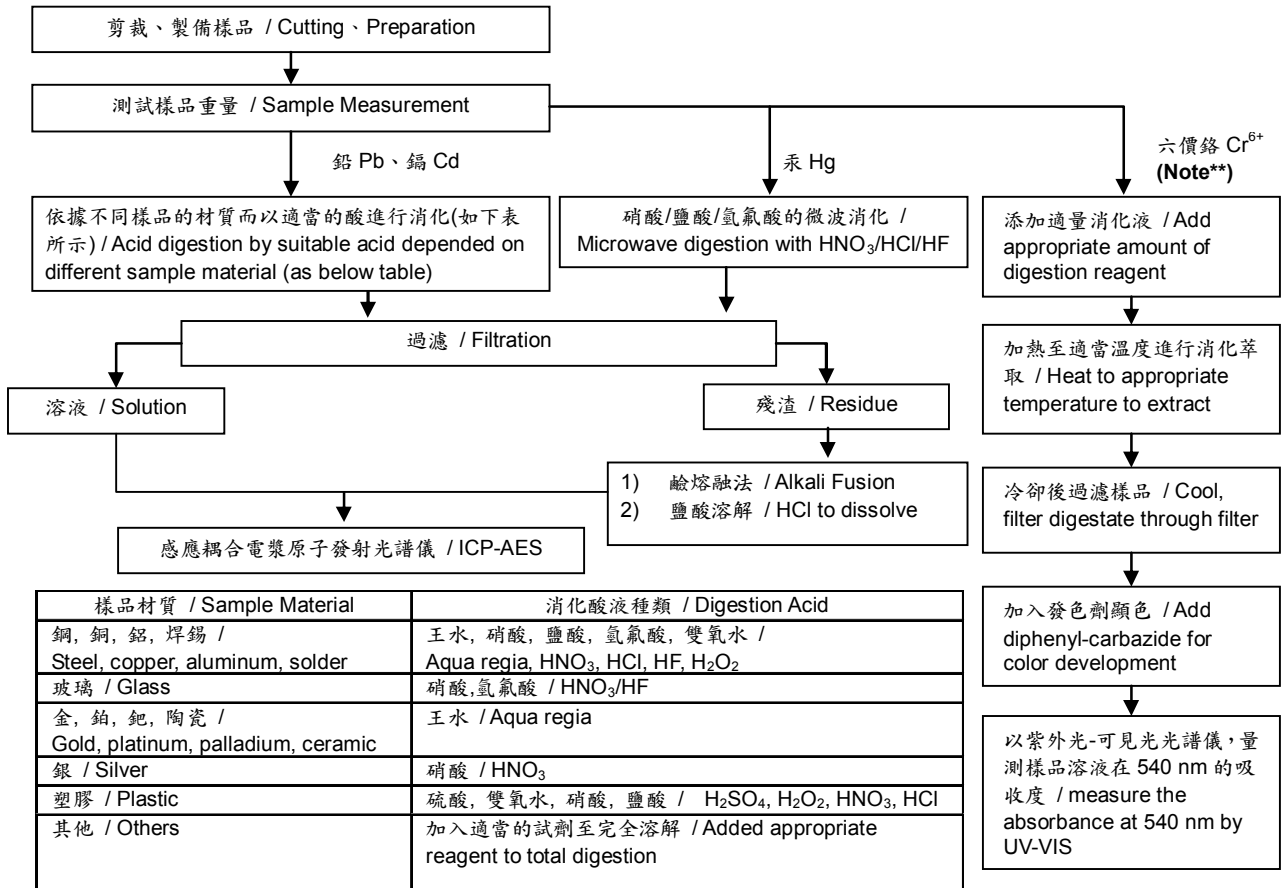
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- 1) 根據以下的流程圖之條件，樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr⁶⁺ test method excluded)
- 2) 測試人員：楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



Note:** (1) 針對非金屬材料加入鹼性消化液，加熱至 90~95°C 萃取。 / For non-metallic material, add alkaline digestion reagent and heat to 90~95°C.
(2) 針對金屬材料加入純水，加熱至沸騰萃取。 / For metallic material, add pure water and heat to boiling.

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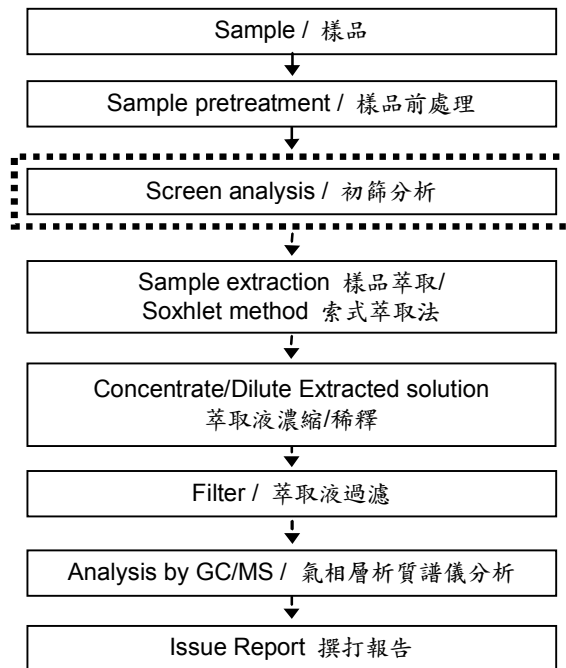
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多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
 - 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang
- 初次測試程序 / First testing process —————>
- 選擇性篩檢程序 / Optional screen process>
- 確認程序 / Confirmation process - - ->



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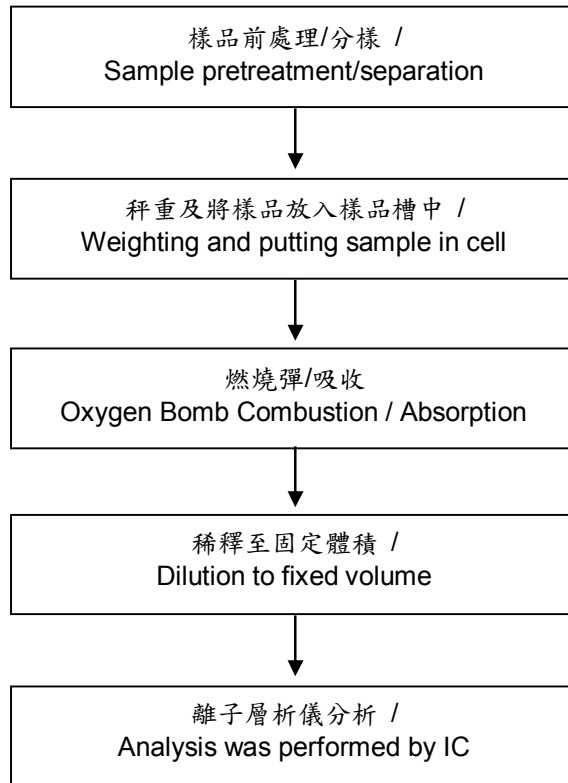
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鹵素分析流程圖 / Analytical flow chart of halogen content

- 測試人員：陳恩臻 / Name of the person who made measurement: Rita Chen
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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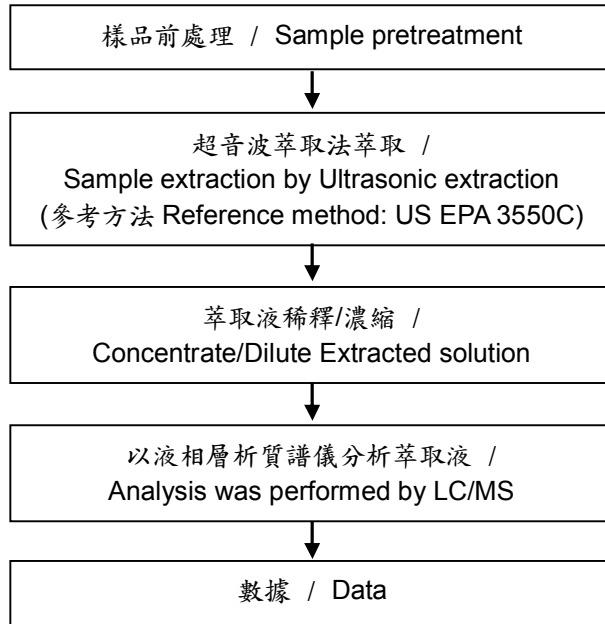
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全氟辛酸/全氟辛烷磺酸分析流程圖 / PFOA/PFOS analytical flow chart

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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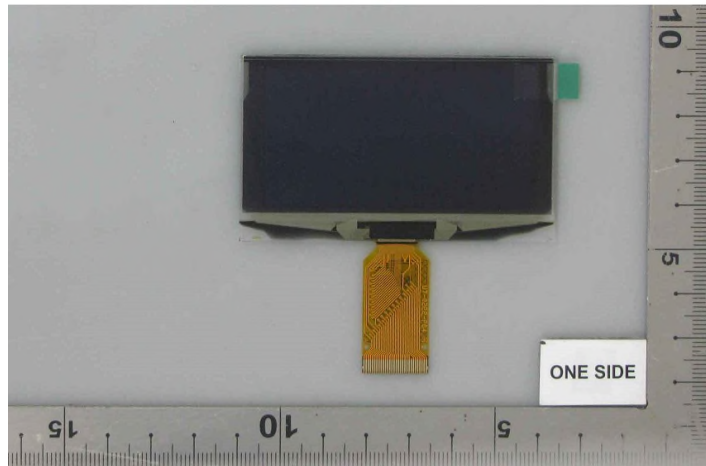
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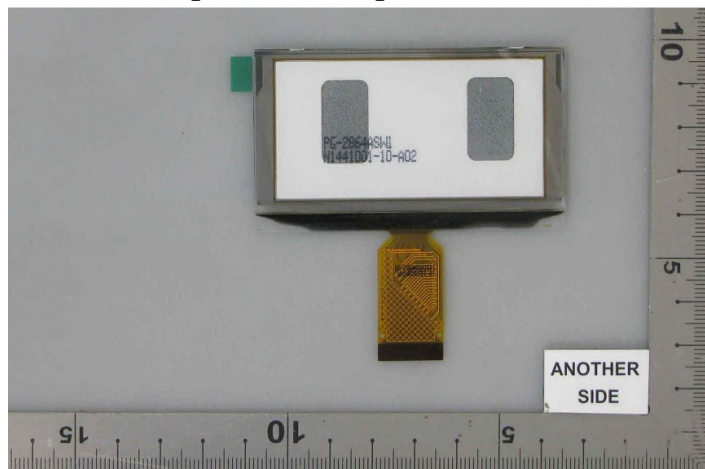


* 照片中如有箭頭標示，則表示為實際檢測之樣品/部位。*
(The tested sample / part is marked by an arrow if it's shown on the photo.)

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** 報告結尾(End of Report) **

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